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Other Documents

Examiner Initial	No.	Author, Title, Date, Place (e.g. Journal) of Publication

Examiner: Initial citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Pg. 3 of 3

Charles Zfl

10/30/02

Form 1449 (Modified)

Information Disclosure Statement By Applicant

(Use Several Sheets if Necessary)

Atty. Docket No.

WÉLLO011

Applicant: Banaugh, et al.

Filing Date:

October 31, 2000

Serial No.:

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